

Notice of References Cited	Application/Control No. 10/679,952	Applicant(s)/Patent Under Reexamination DAVE ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

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	V	Rollins et al, "Optimal Interferometer Designs For Optical Coherence Tomography", OPTICS LETTERS, vol. 24, no. 21, November 1, 1999, pp. 1484-1486.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.